Application/Control No. O9/835,366 Reexamination LAI ET AL. Examiner LEE NGUYEN Applicant(s)/Patent Under Reexamination LAI ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,797,089	08-1998	Nguyen, Nam D.	455/403
	В	US-6,309,305 B1	10-2001	Kraft, Christian A	455/566
	C.	US-2002/0090931 A1	07-2002	Papineau et al.	455/411
	D	US-			
	Ε	US-		·	
	F	US-			
	G	US-			
	Н	US-			
	I	US-			* **
	J	US-			
	к	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*.		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					<u> </u>
	Q					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	٧					
	w					
	х					

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.